



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: DALE HARRISON

Filed: SEPTEMBER 23, 2003

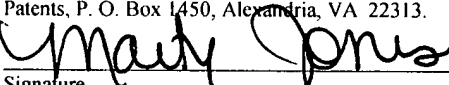
For: VACUUM ULTRAVIOLET REFLECTOMETER SYSTEM AND METHOD

Serial No.: 10/668,642

Group Art Unit: 2878

Examiner: HANNAHER, C.

Atty Dkt: METR:003

<u>EXPRESS MAIL CERTIFICATION</u>	
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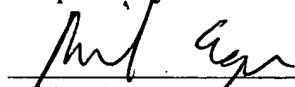
ATTN: OFFICIAL DRAFTSMAN
Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

REQUEST FOR CORRECTION OF DRAWINGS

Please correct FIGS. 18, 19, 20, 21, 22, 24, 25 and 30 of the application drawings as indicated in red ink on the enclosed photocopy.

Respectfully submitted,



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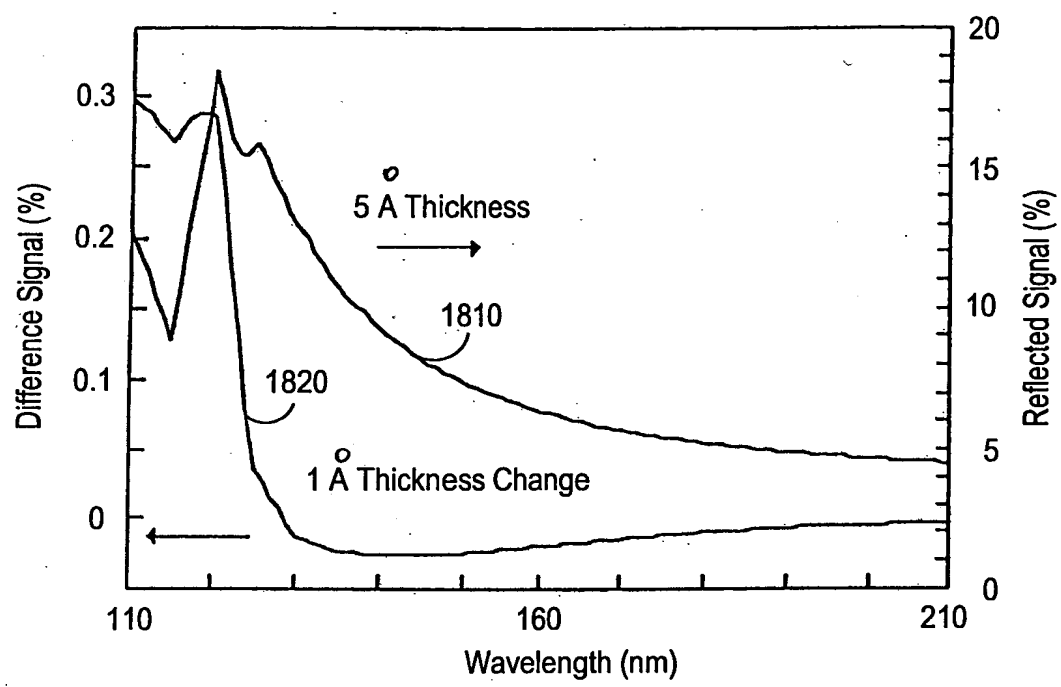


FIG. 18

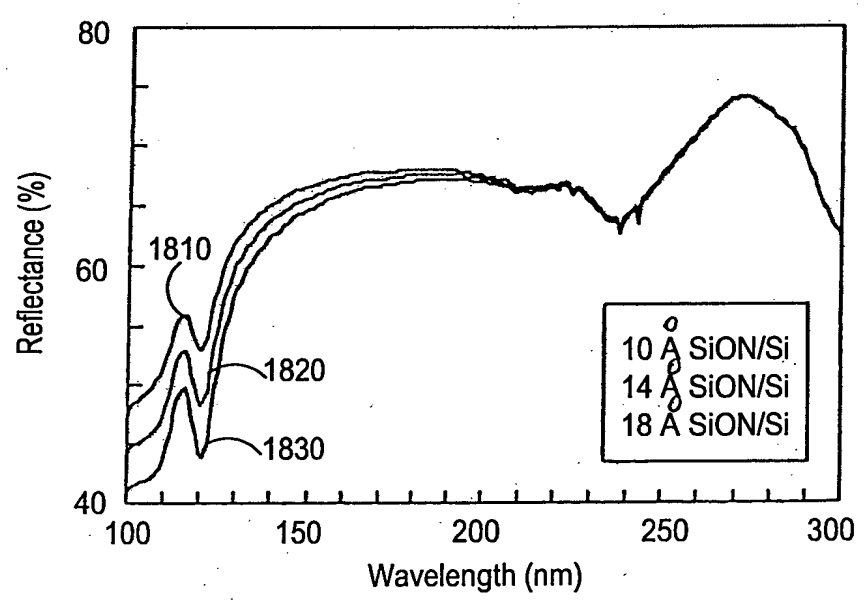


FIG. 19

13% N Layer Nitrided Oxide

Thickness Matrix (10-18 Å)

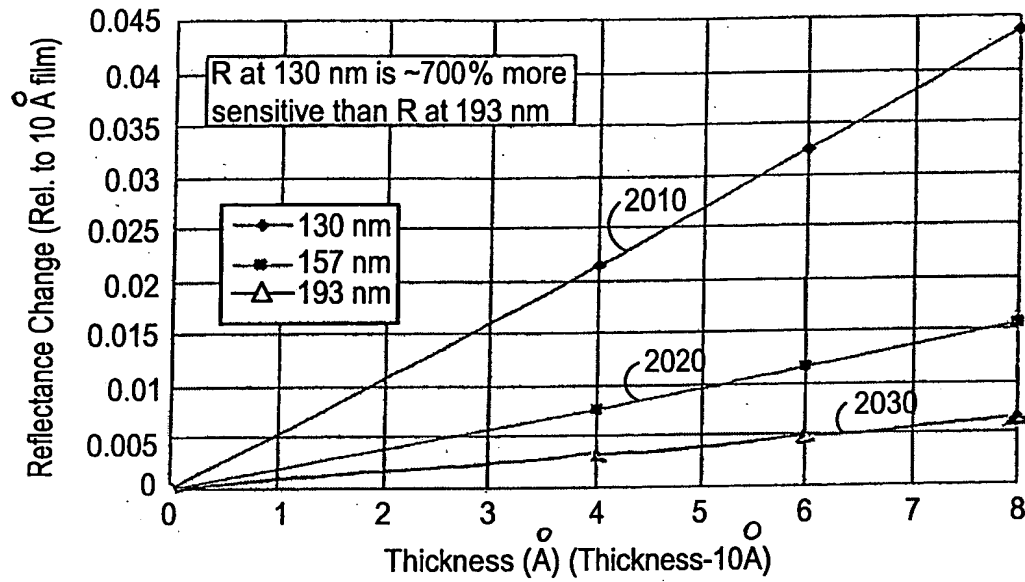


FIG. 20

16 Å Layer of Nitrided Oxide

Nitrogen Matrix (10-15%)

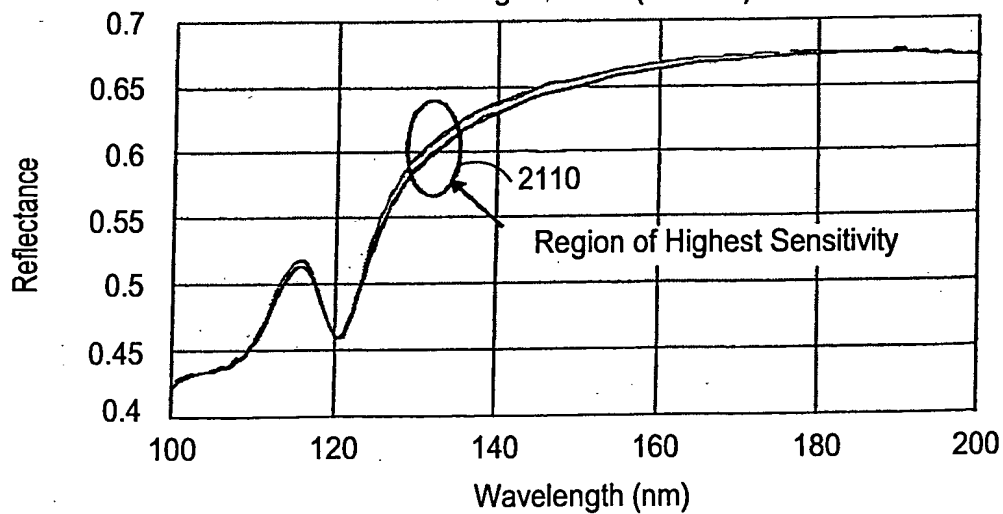


FIG. 21

16 Å Layer Nitrided Oxide

Nitrogen Matrix (10-15%)

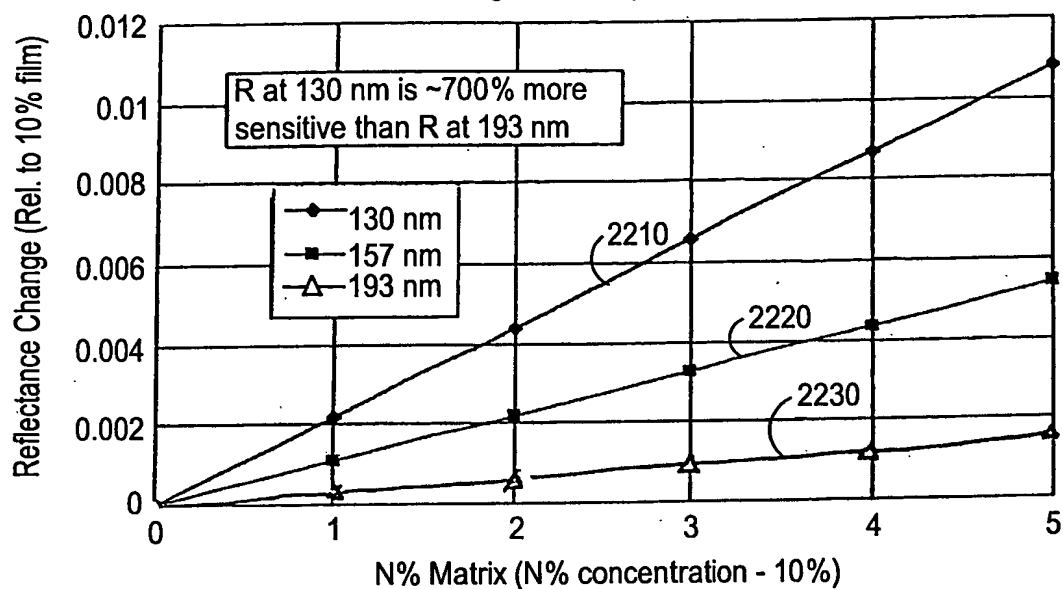


FIG. 22

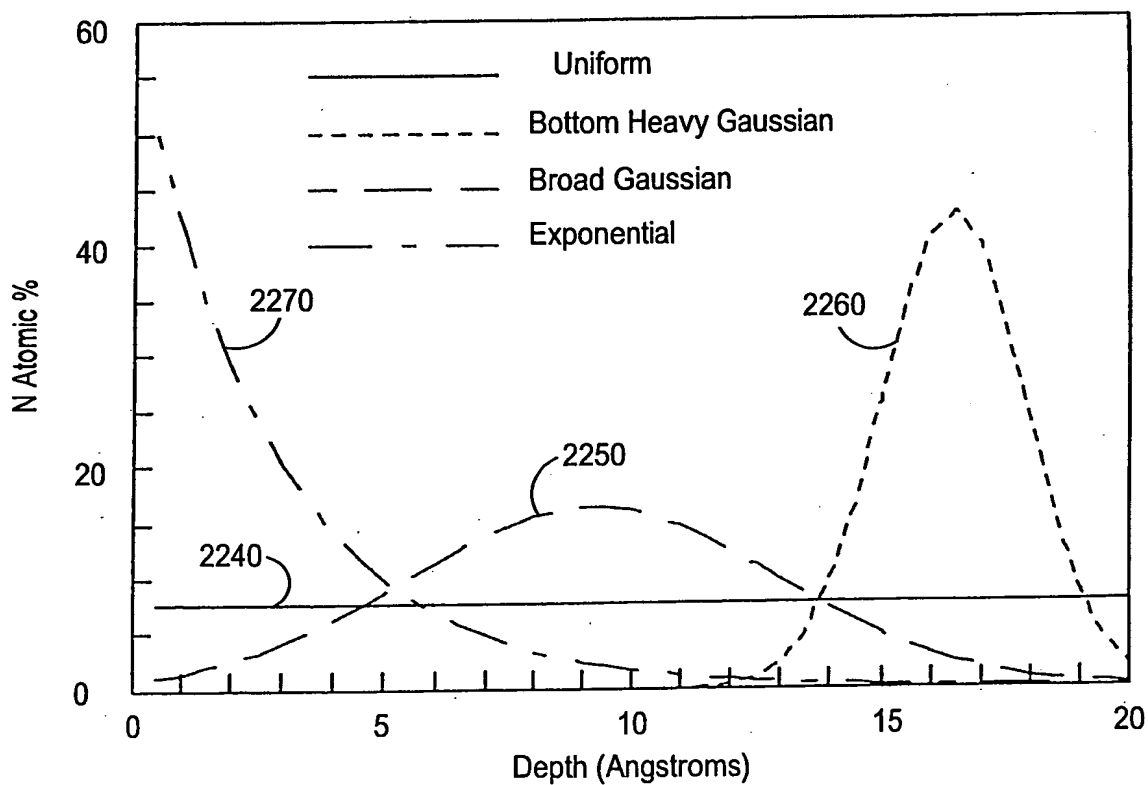


FIG. 22A

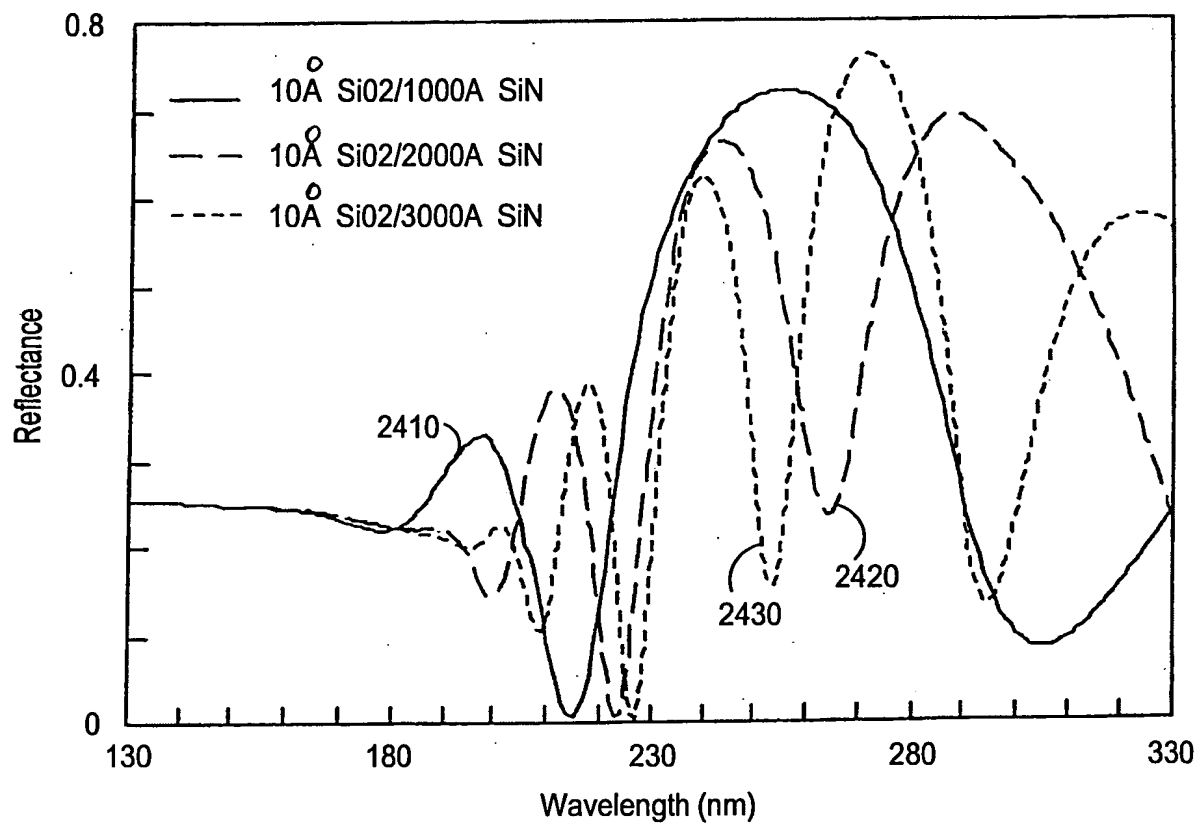


Fig. 24

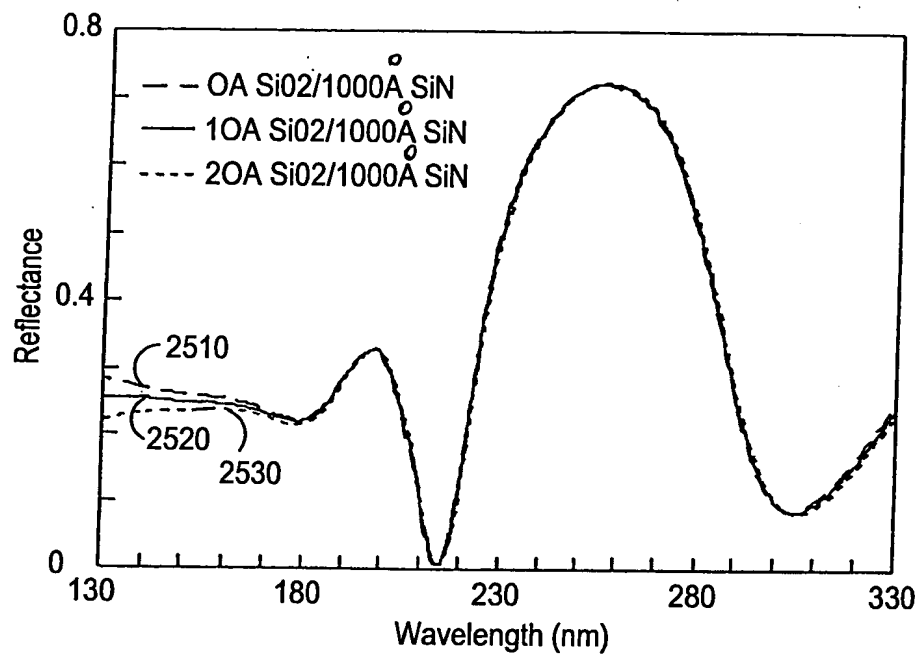


FIG. 25

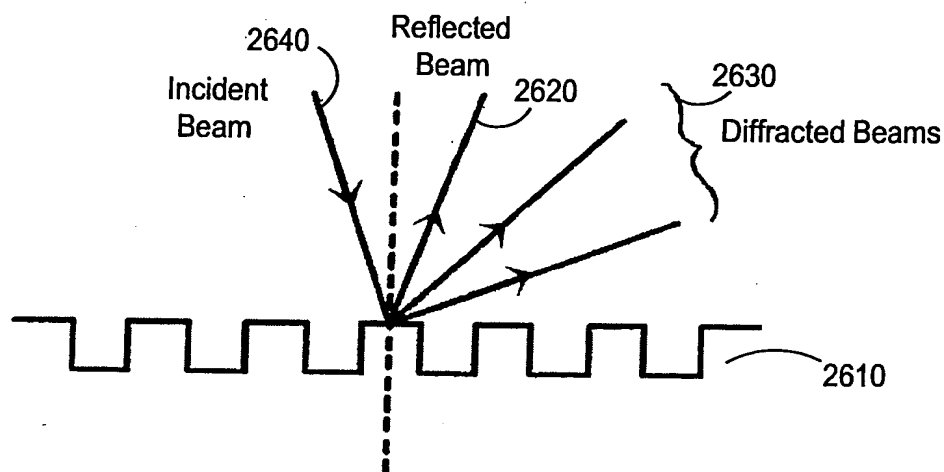


FIG. 26

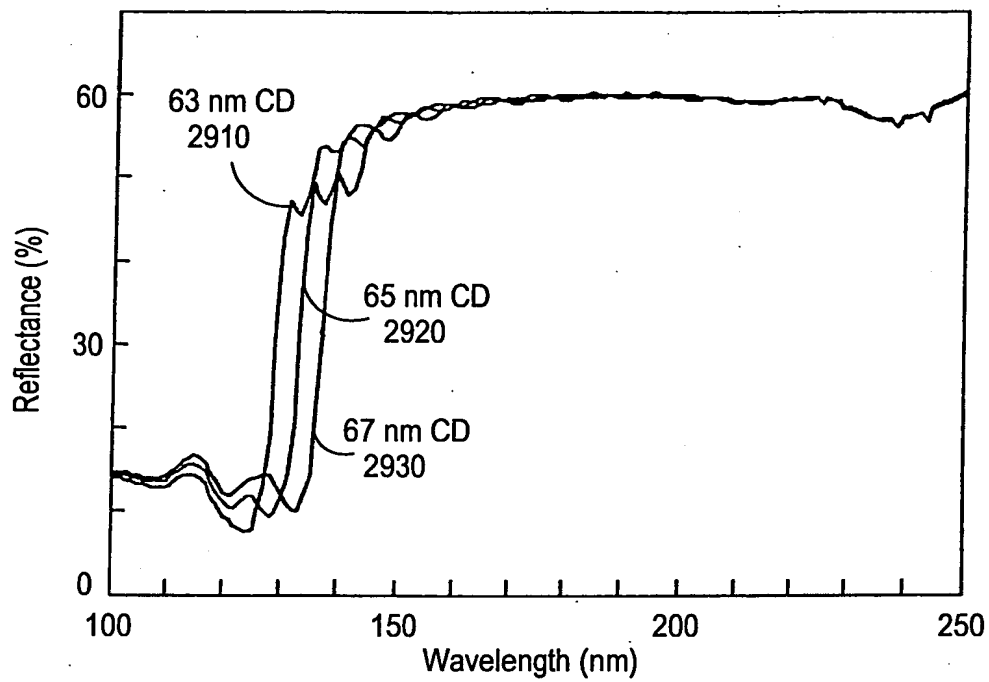


FIG. 29

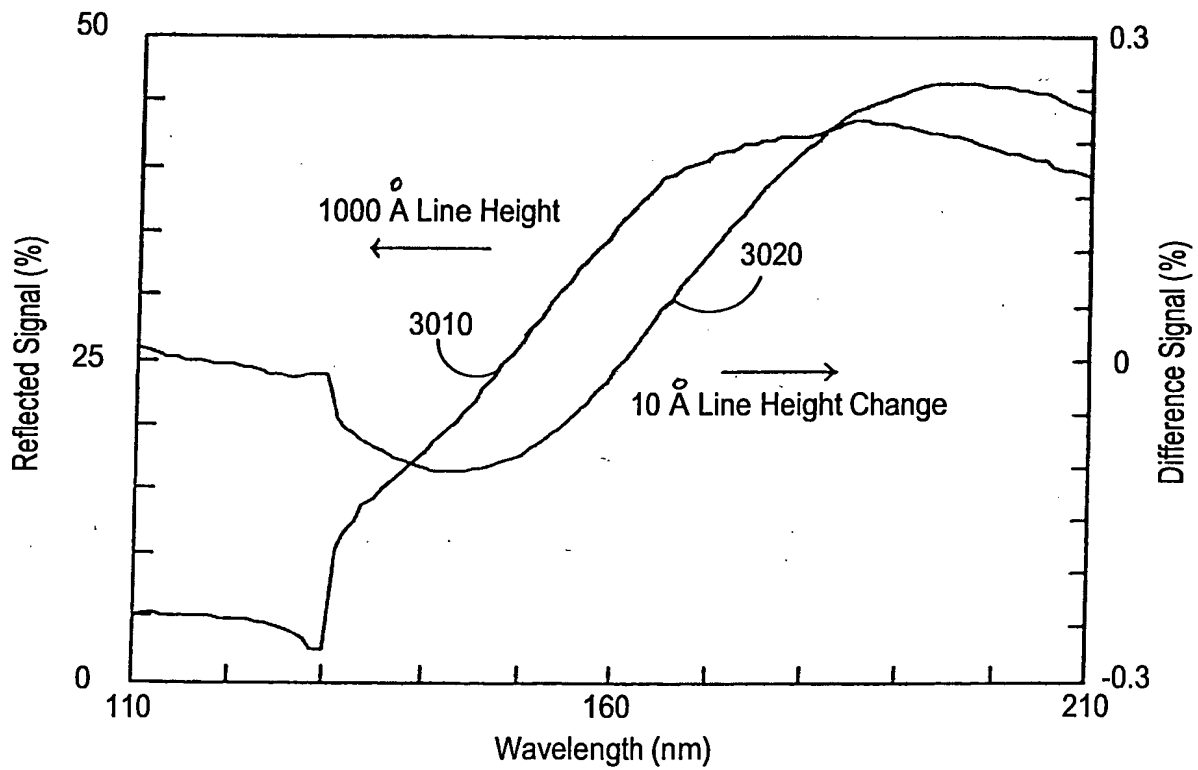


FIG. 30